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## TOETS: Work Package 1

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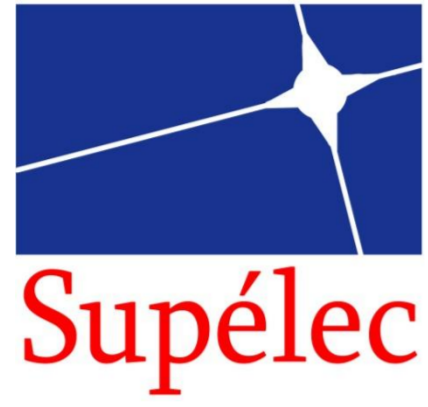
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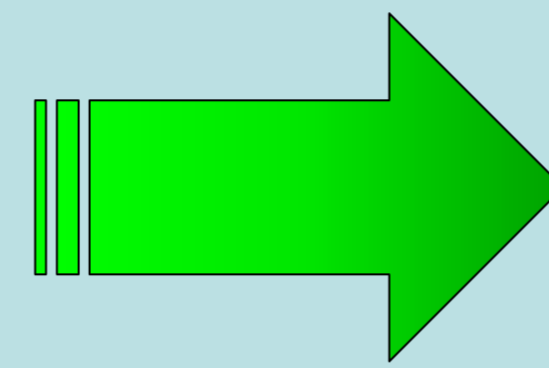
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**Goal: Transform Test features into product Differentiators**



Enhance Access and Control  
Self-repair solutions  
Self-calibration functions



To the integrators  
To end-users

**Major Achievement: Wireless Test Access \* **

**SiP-SoC  
Production  
Test**



▪ **Specific MAC layer: low power, minimal area overhead, reliability**

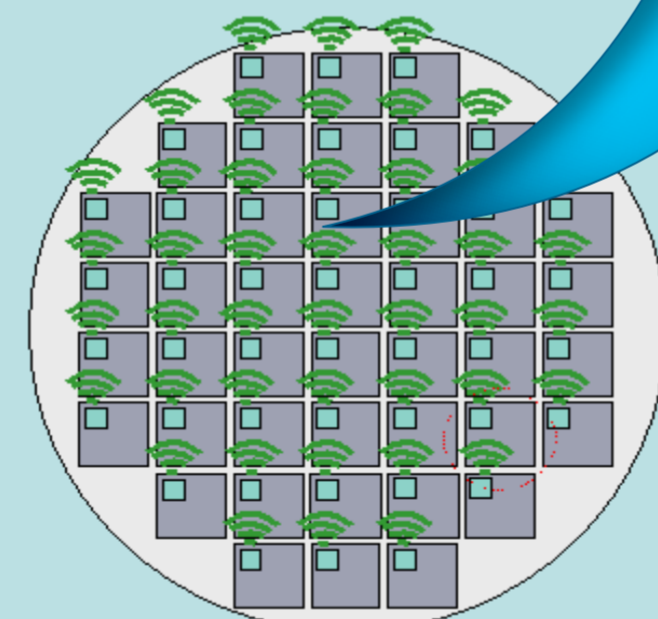
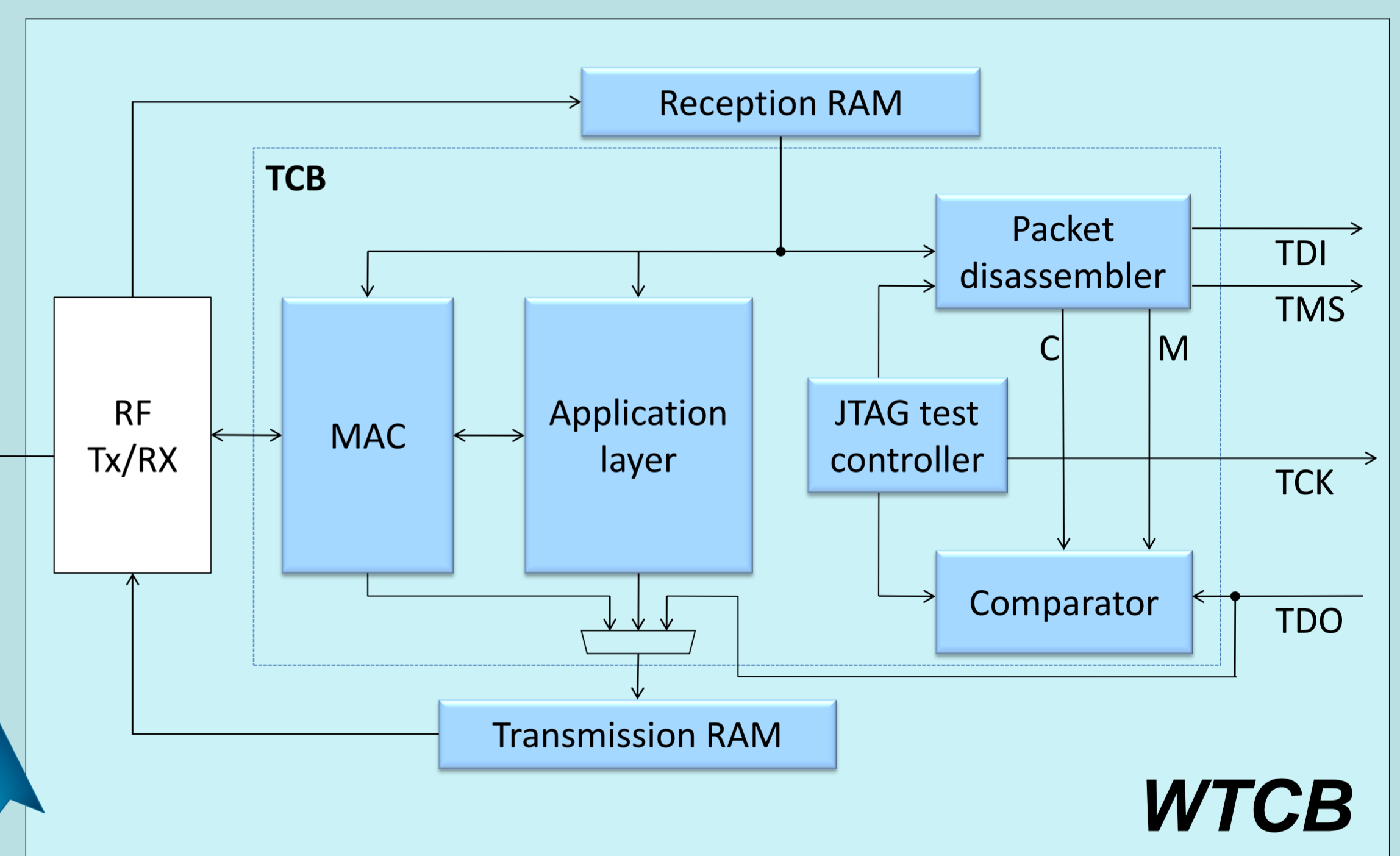
- ✓ Embedded Wireless Test Control Block (WTCB)
- ✓ Test management at circuit level
- ✓ Generic test access

▪ **Adaptive Test Response Handling**

- ✓ Centralized Comparison on ATE for full diagnostic
- ✓ Distributed Comparison on DUTs for test time reduction

▪ **Massive parallel test**

➔ Test time reduction by 4-5



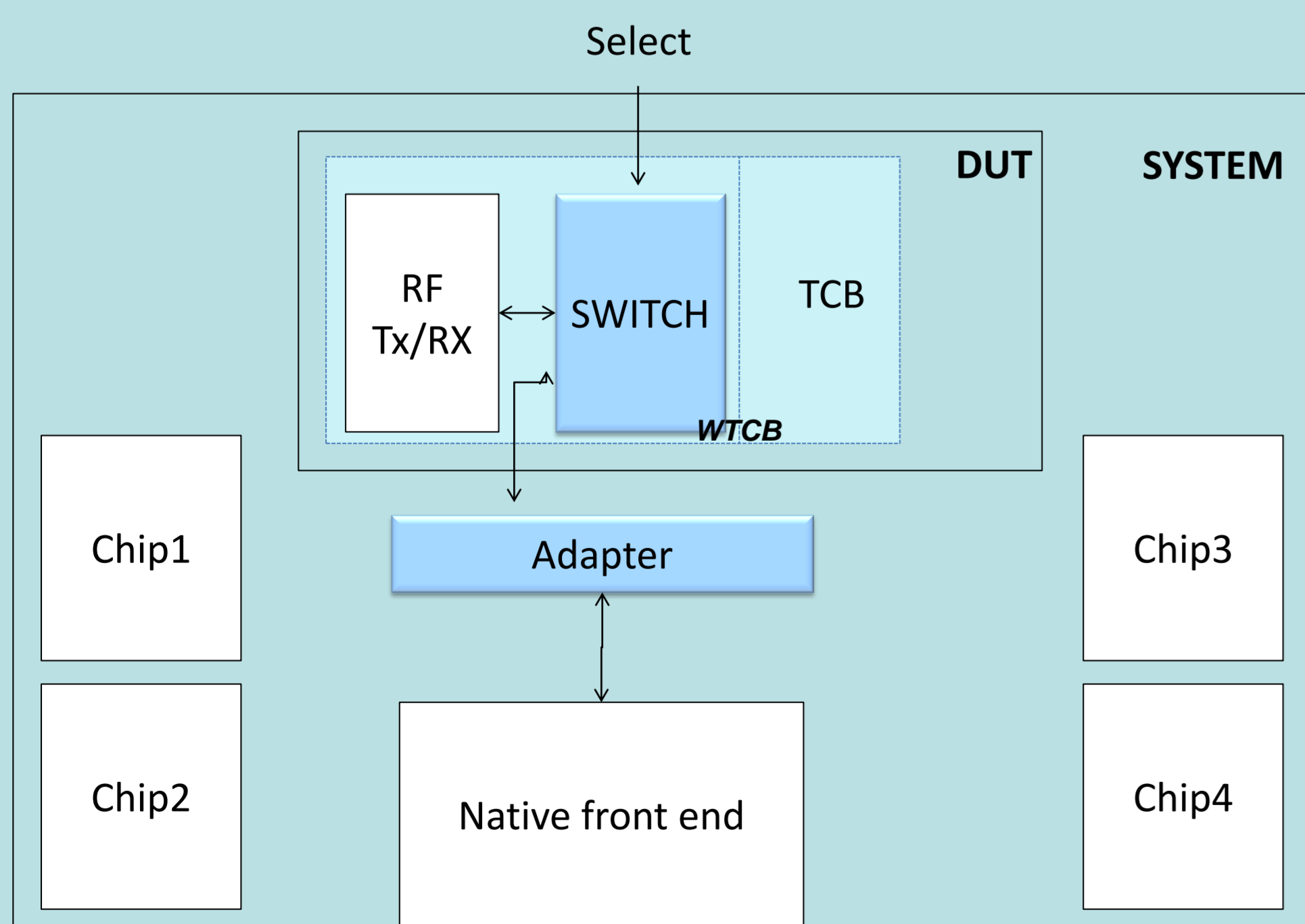
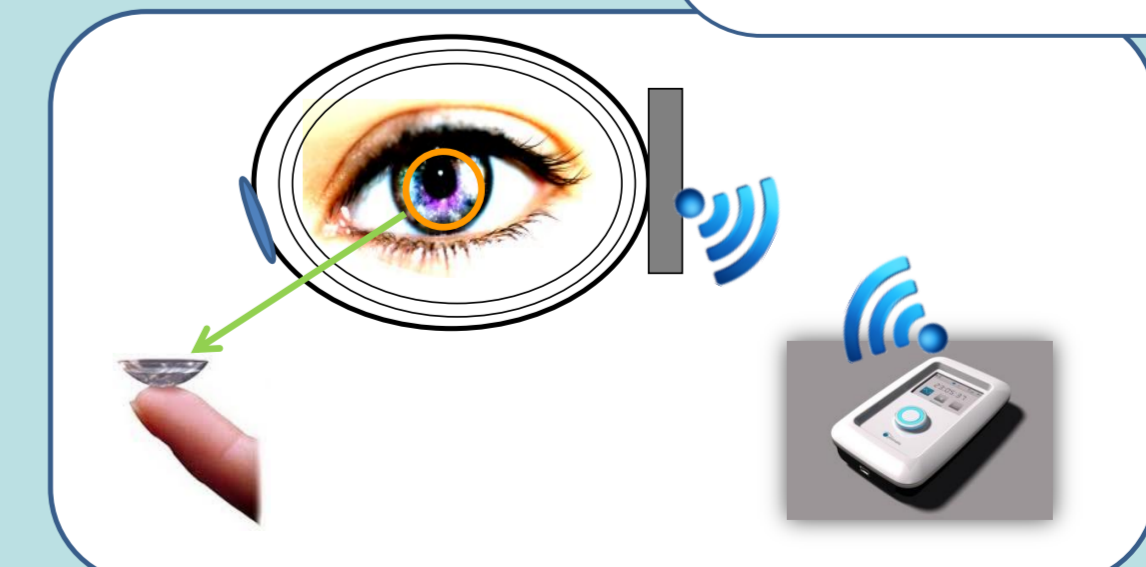
**In-Situ  
Test**

▪ **In Situ/On-line Tests & Diagnostics**

- ✓ Easy maintenance
- ✓ Low cost diagnosis

▪ **Switch**

- ✓ Reuse native wireless frontend
- ✓ Minimal area overhead



\* Works conducted by LIRMM and Optimalia